the contact probe into a hole of the other plate, whereby the probe unit is assembled.

Citation List

Patent Literature

[0004] Patent Literature 1: Japanese Patent Application Laid-open No. 2016-075709

Summary

Technical Problem

[0005] However, with the configuration formed of two plates as mentioned above, in a state where a contact probe has been disposed in a hole of one of plates, there has been a need to laminate the other plate on the one of plates while confirming whether the predetermined contact probe is accommodated in a hole of the other plate. At this time, there has been a case where it is difficult to laminate the other plate so as not to sandwich the contact probe between the plates.

[0006] The present invention has been made in view of the above, and an object is to provide a probe holder and a probe unit that can arrange and dispose a contact probe at a predetermined position of a probe holder certainly and easily.

Solution to Problem

[0007] To solve the above-described problem and achieve the object, a probe holder according to the present invention holds contact probes each of which comes in contact with one electrode of a contact target on one end portion side in a longitudinal direction, and includes a plate in which holder holes configured to hold the respective contact probes are formed and penetrate the probe holder, wherein each of the holder holes includes a first hole portion disposed on one end of a penetrating direction and extending in the penetrating direction, a